

SPW15N60C3

Cool MOS™ Power Transistor

Feature

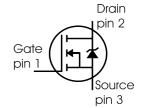
- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- Ultra low effective capacitances
- Improved transconductance
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC⁰⁾ for target applications

V _{DS} @ T _{jmax}	650	٧
R _{DS(on)}	0.28	Ω
/ _D	15	Α





Туре	Package	Ordering Code	Marking
SPW15N60C3	PG-TO247	Q67040-S4604	15N60C3



Maximum Ratings

Parameter	Symbol	Value	Unit
Continuous drain current	I _D		А
$T_{\rm C}$ = 25 °C		15	
<i>T</i> _C = 100 °C		9.4	
Pulsed drain current, t_p limited by T_{jmax}	I _{D puls}	45	
Avalanche energy, single pulse	E _{AS}	460	mJ
$I_{\rm D}$ = 7.5 A, $V_{\rm DD}$ = 50 V			
Avalanche energy, repetitive t_{AR} limited by T_{jmax}^{1}	E _{AR}	0.8	
$I_{\rm D}$ = 15 A, $V_{\rm DD}$ = 50 V			
Avalanche current, repetitive t_{AR} limited by T_{jmax}	I _{AR}	15	А
Reverse diode dv/dt	d <i>v</i> /d <i>t</i>	6	V/ns
I _S =15A, V _{DS} =480V, T _i =125°C			
Gate source voltage static	V_{GS}	±20	V
Gate source voltage AC (f >1Hz)	V_{GS}	±30	
Power dissipation, $T_C = 25^{\circ}C$	P _{tot}	156	W
Operating and storage temperature	T _j , T _{stg}	-55 +150	°C





Maximum Ratings

Parameter	Symbol	Value	Unit
Drain Source voltage slope	d <i>v</i> /d <i>t</i>	50	V/ns
$V_{\rm DS}$ = 480 V, $I_{\rm D}$ = 15 A, $T_{\rm j}$ = 125 °C			

Thermal Characteristics

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Thermal resistance, junction - case	R _{thJC}	-	-	0.8	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	62	
Soldering temperature, wavesoldering	T_{sold}	-	-	260	°C
1.6 mm (0.063 in.) from case for 10s					

Electrical Characteristics, at Tj=25°C unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0V, I _D =0.25mA	600	-	-	V
Drain-Source avalanche	V _{(BR)DS}	V _{GS} =0V, I _D =15A	-	700	-	
breakdown voltage						
Gate threshold voltage	V _{GS(th)}	$I_{\rm D}$ =675 $\mu{\rm A},\ V_{\rm GS}$ = $V_{\rm DS}$	2.1	3	3.9	
Zero gate voltage drain current	I _{DSS}	V _{DS} =600V, V _{GS} =0V,				μA
		<i>T</i> j=25°C,	-	0.1	1	
		<i>T</i> _j =150°C	-	-	100	
Gate-source leakage current	I _{GSS}	V _{GS} =30V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10V, I _D =9.4A,				Ω
	, ,	<i>T</i> j=25°C	-	0.25	0.28	
		T _j =150°C	-	0.68	_	
Gate input resistance	R _G	f=1MHz, open Drain	-	1.23	-	1



Electrical Characteristics , at $T_{\rm j}$ = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Transconductance	<i>g</i> fs	V _{DS} ≥2*I _D *R _{DS(on)max} ,	-	11.9	-	S
		I _D =9.4A				
Input capacitance	C _{iss}	V _{GS} =0V, V _{DS} =25V,	-	1660	-	pF
Output capacitance	Coss	f=1MHz	-	540	-	
Reverse transfer capacitance	C _{rss}		-	40	-	
Effective output capacitance,2)		V _{GS} =0V,	-	80	-	pF
energy related	, ,	V _{DS} =0V to 480V				
Effective output capacitance,3)	C _{o(tr)}		-	127	-	
time related	, ,					
Turn-on delay time	t _{d(on)}	V _{DD} =380V, V _{GS} =0/10V,	1	10	-	ns
Rise time	$t_{\rm r}$	$I_{\rm D}$ =15A, $R_{\rm G}$ =4.3Ω	-	5	-	
Turn-off delay time	t _{d(off)}		-	50	80	
Fall time	<i>t</i> _f		-	5	10	

Gate Charge Characteristics

Gate to source charge	Q _{gs}	V _{DD} =480V, I _D =15A	-	7	-	nC
Gate to drain charge	Q _{gd}		-	29	-	
Gate charge total	Qg	V _{DD} =480V, I _D =15A,	-	63	-	
		V _{GS} =0 to 10V				
Gate plateau voltage	V _(plateau)	V _{DD} =480V, I _D =15A	-	5	-	V

⁰J-STD20 and JESD22

¹Repetitve avalanche causes additional power losses that can be calculated as $P_{\text{AV}} = E_{\text{AR}} * f$.

 $^{^2}C_{\mathrm{o(er)}}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

 $^{^3}C_{\mathrm{o(tr)}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

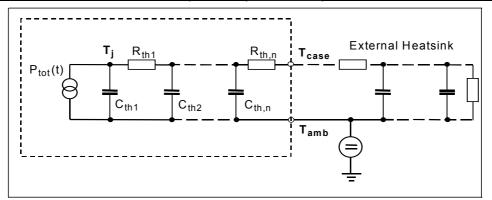


Electrical Characteristics, at T_j = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Inverse diode continuous	IS	<i>T</i> _C =25°C	-	-	15	Α
forward current						
Inverse diode direct current,	I _{SM}		-	-	45	
pulsed						
Inverse diode forward voltage	V_{SD}	V _{GS} =0V, I _F =I _S	-	1	1.2	V
Reverse recovery time	t_{rr}	V _R =480V, I _F =I _S ,	-	460	-	ns
Reverse recovery charge	Q _{rr}	d <i>i</i> _F /d <i>t</i> =100A/μs	-	27	-	μC
Peak reverse recovery current	/ _{rrm}		-	55	-	Α
Peak rate of fall of reverse	di _{rr} /dt		-	tbd	-	A/µs
recovery current						

Typical Transient Thermal Characteristics

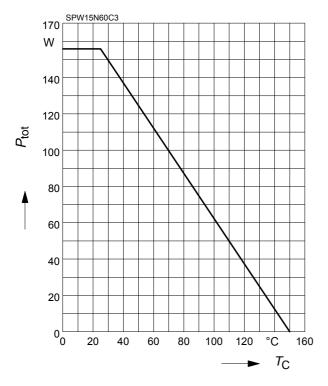
Symbol	Value	Unit	Symbol	Value	Unit
	typ.			typ.	
Thermal r	esistance		Thermal of	capacitance	·
R _{th1}	0.012	K/W	C _{th1}	0.0002495	Ws/K
R _{th2}	0.023		C _{th2}	0.0009406	
R _{th3}	0.043		C _{th3}	0.001298	
R _{th4}	0.156		C _{th4}	0.00362	
R _{th5}	0.178		C _{th5}	0.009046	
R _{th6}	0.072		C _{th6}	0.412	





1 Power dissipation

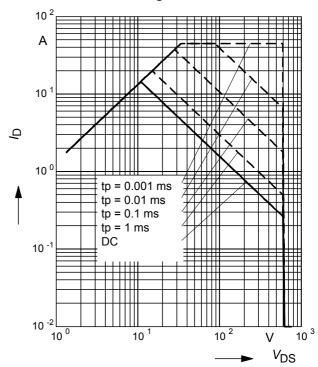
$$P_{\text{tot}} = f(T_{\text{C}})$$



2 Safe operating area

$$I_{\mathsf{D}} = f(\ V_{\mathsf{DS}}\)$$

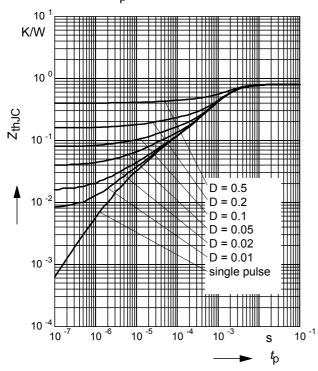
parameter : D = 0 , $T_C = 25$ °C



3 Transient thermal impedance

$$Z_{\mathsf{thJC}} = f\left(t_{\mathsf{p}}\right)$$

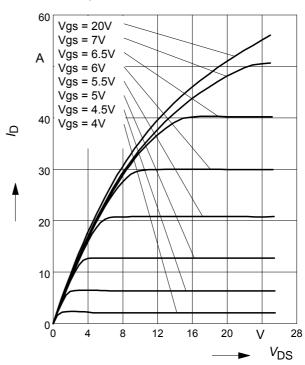
parameter: $D = t_D/T$



4 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{j}=25^{\circ}C$

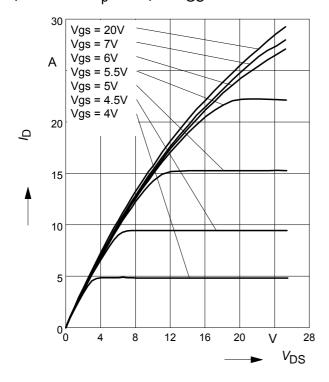
parameter: t_p = 10 μ s, V_{GS}





5 Typ. output characteristic

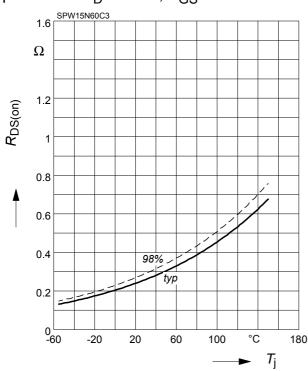
 $I_{\rm D}$ = $f(V_{\rm DS})$; $T_{\rm j}$ =150°C parameter: $t_{\rm p}$ = 10 μ s, $V_{\rm GS}$



7 Drain-source on-state resistance

 $R_{\mathrm{DS}(\mathrm{on})} = f(T_{\mathrm{j}})$

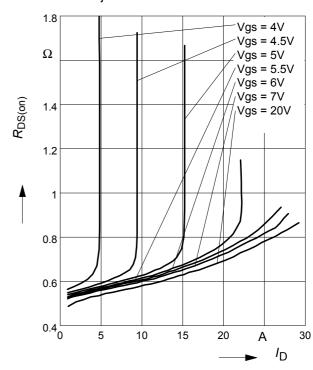
parameter : I_D = 9.4 A, V_{GS} = 10 V



6 Typ. drain-source on resistance

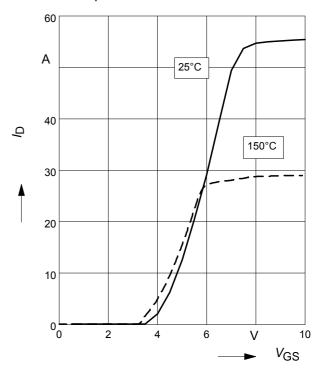
 $R_{DS(on)} = f(I_D)$

parameter: T_i =150°C, V_{GS}



8 Typ. transfer characteristics

 $I_{\rm D}$ = $f(V_{\rm GS})$; $V_{\rm DS}$ $\geq 2 \times I_{\rm D} \times R_{\rm DS(on)max}$ parameter: $t_{\rm p}$ = 10 μ s

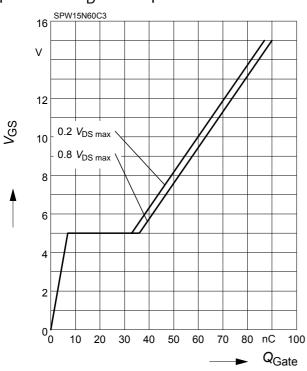




9 Typ. gate charge

 $V_{GS} = f (Q_{Gate})$

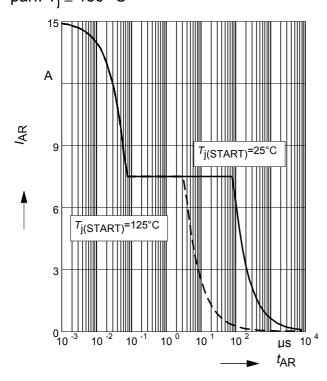
parameter: I_D = 15 A pulsed



11 Avalanche SOA

 $I_{AR} = f(t_{AR})$

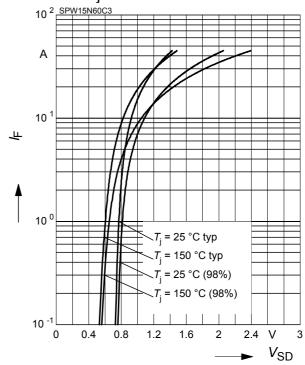
par.: $T_j \le 150 \, ^{\circ}\text{C}$



10 Forward characteristics of body diode

 $I_{\mathsf{F}} = f(\mathsf{V}_{\mathsf{SD}})$

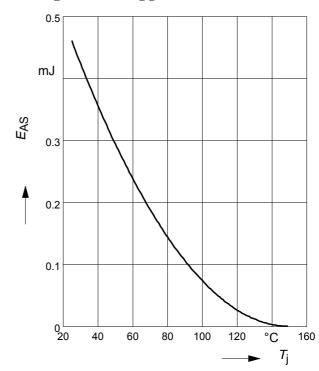
parameter: T_{j} , tp = 10 μ s



12 Avalanche energy

 $E_{AS} = f(T_i)$

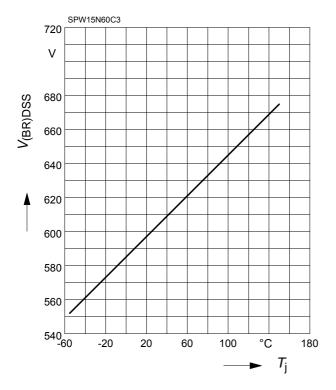
par.: $I_D = 7.5 \text{ A}, V_{DD} = 50 \text{ V}$





13 Drain-source breakdown voltage

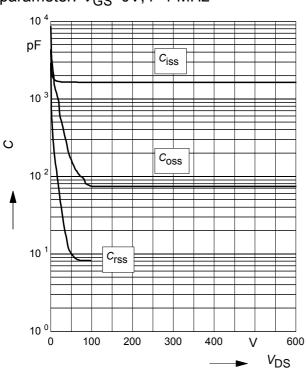
$$V_{(BR)DSS} = f(T_j)$$



15 Typ. capacitances

$$C = f(V_{DS})$$

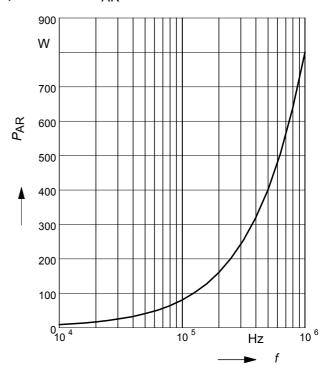
parameter: V_{GS} =0V, f=1 MHz



14 Avalanche power losses

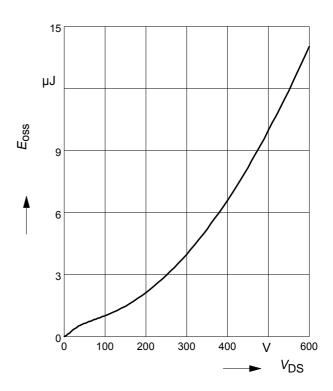
$$P_{AR} = f(f)$$

parameter: E_{AR}=0.8mJ



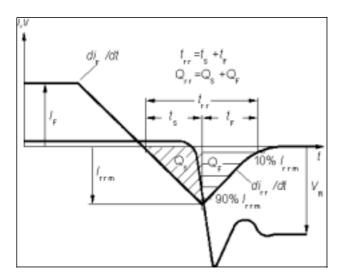
16 Typ. $C_{\rm OSS}$ stored energy

$$E_{\text{oss}} = f(V_{\text{DS}})$$



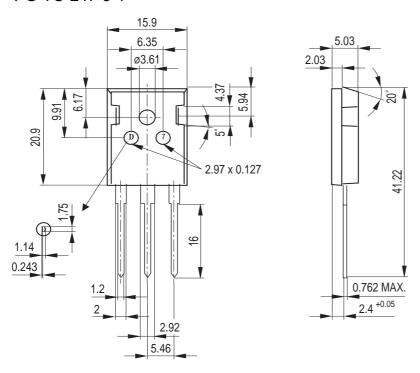


Definition of diodes switching characteristics





PG-TO-247-3-1



General tolerance unless otherwise specified: Leadframe parts: ± 0.05 Package parts: ± 0.12



Published by Infineon Technologies AG, Bereichs Kommunikation St.-Martin-Strasse 53, D-81541 München © Infineon Technologies AG 1999 All Rights Reserved.

Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office in Germany or our Infineon Technologies Reprensatives worldwide (see address list).

Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies Components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system Life support devices or systems are intended to be implanted in the human body, or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.